

INFD065C2004S2W01A

◇ 650V 200mΩ D-Mode GaN HEMT Preliminary wafer datasheet

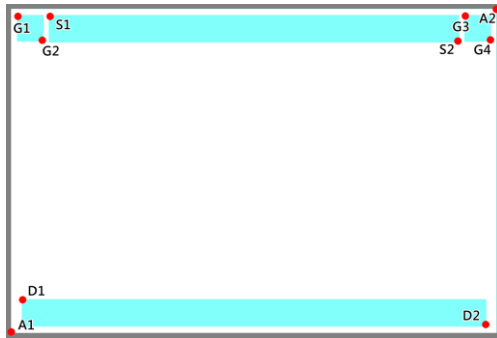
Applications

- Power Adapters / Converter
- PFC Application
- Appliance Motor Drives
- Wireless Power Transfer
- Synchronous Rectifier for Application

Key Features

Parameter	Value	Unit
BV_{DSS}	650	V
I_D	10	A
Die Size	2544x1714	um
Gross Die	1465	ea

Chip Size & Pad Position (unit: um)



Die w/o scribe line(50um)

A1(0,0), A2(2494,1664)

Gate

G1(31,1633), G2(191,1498)

G3(2328,1633), G4(3463,1498)

Source

S1(194,1633), S2(2301,1493)

Source

D1(56,173), D2(2439,33)

Die Descriptions

- Wafer Size: 4 inch (± 0.1 inches)
- Wafer THK: 650 ± 25 um
- Die Size: 2544x1714 um
- Scribe Line Width: 50 um
- Pad Metal: Al
- Metal Thickness: 4um
- Bonding Area:
 - Gate: 135*135
 - Drain: 2383*140
 - Source: 2107*140
- GDPW: 1465 ea (E.E=2mm)

Static Electrical Characteristic (T_A = 25 °C unless otherwise noted)

Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Drain-Source Breakdown Voltage	BV _{DSS}	V _G =-22 V, I _D =10 uA,	650			V
Gate Threshold Voltage	V _{GS(th)}	V _D =10V, I _D =1 mA	-18	-15	-12	V
Gate -Source Leakage Current	I _{GSS}	V _D = 0V, V _G =-22 V	-		100	nA
Drain-Source Leakage Current	I _{DSS}	V _D =650 V, V _G =-22 V	-		1	uA
Drain-Source on-state Resistance	R _{DS(on)}	I _D =2 A, V _G =0 V	-	200		mohm
Drain Current @T=25°C	I _D	V _D =10V, V _G =+1V	-	10	-	A

1) Performance will vary based on assembly technique and substrate of choice